

# BLM6G22-30; BLM6G22-30G

W-CDMA 2100 MHz to 2200 MHz power MMIC

Rev. 4 — 7 March 2011

Product data sheet

## 1. Product profile

### 1.1 General description

30 W LDMOS 2-stage power MMIC for base station applications at frequencies from 2100 MHz to 2200 MHz. Available in gull wing for surface mount (SOT822-1) or flat lead (SOT834-1).

**Table 1. Typical performance**

Typical RF performance at  $T_h = 25^\circ\text{C}$ .

Mode of operation	f (MHz)	V <sub>DS</sub> (V)	P <sub>L(AV)</sub> (W)	G <sub>p</sub> (dB)	η <sub>ID</sub> (%)	IMD3 (dBc)	ACPR (dBc)
2-carrier W-CDMA	2110 to 2170	28	2	29.5	9	-48 <sup>[1]</sup>	-50 <sup>[1]</sup>

[1] Test signal: 3GPP; test model 1; 64 DPCH; PAR = 7 dB at 0.01 % probability on CCDF per carrier; carrier spacing 10 MHz.

#### CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

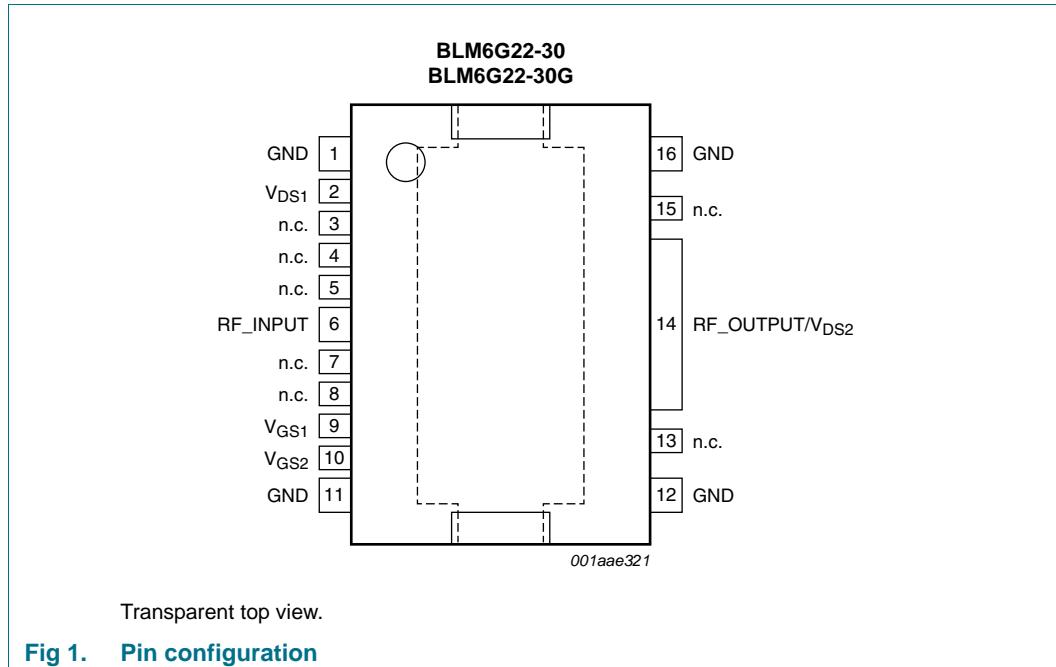
### 1.2 Features and benefits

- Typical 2-carrier W-CDMA performance at a frequency of 2110 MHz:
  - ◆ Average output power = 2 W
  - ◆ Power gain = 30 dB (typ)
  - ◆ Efficiency = 9 %
  - ◆ IMD3 = -48 dBc
  - ◆ ACPR = -50 dBc
- Integrated temperature compensated bias
- Excellent thermal stability
- Biasing of individual stages is externally accessible
- Integrated ESD protection
- Small component size, very suitable for PA size reduction
- On-chip matching (input matched to 50 Ohm, output partially matched)
- High power gain
- Designed for broadband operation (2100 MHz to 2200 MHz)
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)



## 2. Pinning information

### 2.1 Pinning



### 2.2 Pin description

**Table 2. Pin description**

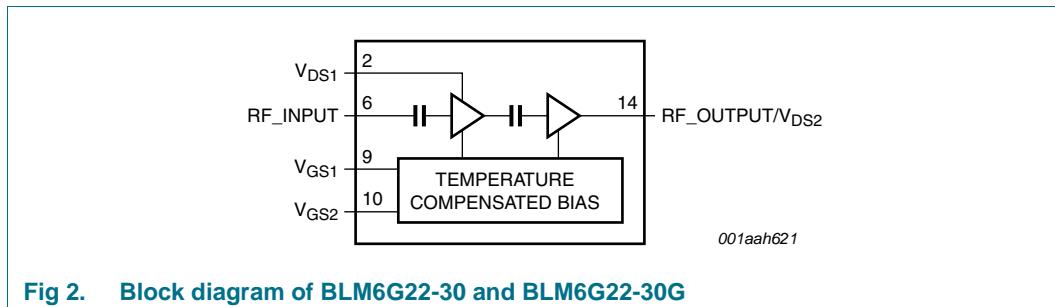
Symbol	Pin	Description
GND	1, 11, 12, 16	ground
V <sub>DS1</sub>	2	first stage drain-source voltage
n.c.	3, 4, 5, 7, 8, 13, 15	not connected
RF_INPUT	6	RF input
V <sub>GS1</sub>	9	first stage gate-source voltage
V <sub>GS2</sub>	10	second stage gate-source voltage
RF_OUT/V <sub>DS2</sub>	14	RF output or second stage drain-source voltage
RF_GND	flange	RF ground

## 3. Ordering information

**Table 3. Ordering information**

Type number	Package		
	Name	Description	Version
BLM6G22-30	HSOP16F	plastic, heatsink small outline package; 16 leads (flat)	SOT834-1
BLM6G22-30G	HSOP16	plastic, heatsink small outline package; 16 leads	SOT822-1

## 4. Block diagram



## 5. Limiting values

**Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	65	V
$V_{GS}$	gate-source voltage		0.5	+13	V
$I_{D1}$	first stage drain current		-	3	A
$I_{D2}$	second stage drain current		-	9	A
$T_{stg}$	storage temperature		-65	+150	°C
$T_j$	junction temperature		-	200	°C

## 6. Thermal characteristics

**Table 5. Thermal characteristics**

Symbol	Parameter	Conditions	Value	Unit
$R_{th(j-c)1}$	first stage thermal resistance from junction to case	$T_{case} = 25 \text{ °C}; P_L = 2 \text{ W};$ 2-carrier W-CDMA	[1] 3.9	K/W
$R_{th(j-c)2}$	second stage thermal resistance from junction to case	$T_{case} = 25 \text{ °C}; P_L = 2 \text{ W};$ 2-carrier W-CDMA	[1] 2.1	K/W

[1] Thermal resistance is determined under specific RF operating conditions.

## 7. Characteristics

**Table 6. Characteristics**

Mode of operation: 2-carrier W-CDMA; PAR 7 dB at 0.01 % probability on CCDF;  
 3GPP test model 1; 1-64 PDPCH;  $f_1 = 2112.5$  MHz;  $f_2 = 2122.5$  MHz;  $f_3 = 2157.5$  MHz;  
 $f_4 = 2167.5$  MHz;  $V_{DS} = 28$  V;  $I_{Dq1} = 270$  mA;  $I_{Dq2} = 280$  mA;  $T_h = 25$  °C unless otherwise specified;  
 in a production test circuit as described in [Section 9 "Test information"](#).

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$G_p$	power gain	$P_{L(AV)} = 2$ W	27.5	30	32.5	dB
$RL_{in}$	input return loss	$P_{L(AV)} = 2$ W	-	-14	-10	dB
$\eta_D$	drain efficiency	$P_{L(AV)} = 2$ W	7.5	9	-	%
IMD3	third-order intermodulation distortion	$P_{L(AV)} = 2$ W	-	-48	-44.5	dBc
ACPR	adjacent channel power ratio	$P_{L(AV)} = 2$ W	-	-50	-47	dBc

## 8. Application information

### 8.1 Ruggedness

The BLM6G22-30 and BLM6G22-30G are capable of withstanding a load mismatch corresponding to  $VSWR = 5 : 1$  through all phases under the following conditions:  
 $V_{DS} = 28$  V;  $I_{Dq1} = 270$  mA;  $I_{Dq2} = 280$  mA;  $P_L = 2$  W; 2-carrier W-CDMA.

### 8.2 Impedance information

**Table 7. Typical impedance**

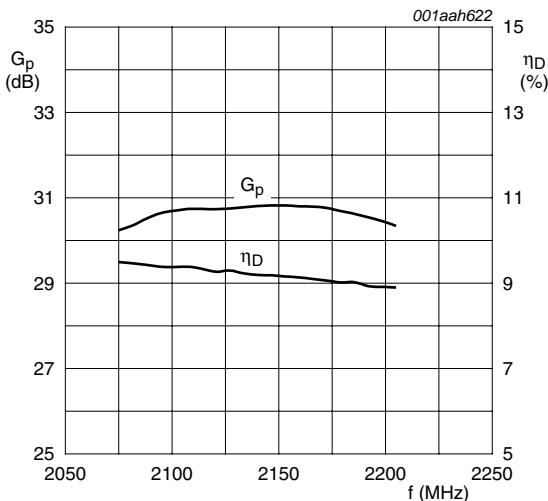
<b>f</b> <b>MHz</b>	<b><math>Z_i</math> [1]</b> $\Omega$	<b><math>Z_L</math> [2]</b> $\Omega$
2075	$40.9 + j22.8$	$18.0 - j5.5$
2085	$41.2 + j23.2$	$17.8 - j5.6$
2095	$41.6 + j23.3$	$17.7 - j5.7$
2105	$41.9 + j23.3$	$17.7 - j5.9$
2115	$42.1 + j23.3$	$17.6 - j6.0$
2125	$42.2 + j23.2$	$17.4 - j6.0$
2135	$42.4 + j23.1$	$17.3 - j6.1$
2145	$42.3 + j22.9$	$17.2 - j6.1$
2155	$42.5 + j22.8$	$17.0 - j6.2$
2165	$42.6 + j22.8$	$16.8 - j6.3$
2175	$42.7 + j22.8$	$16.6 - j6.4$
2185	$43.0 + j23.0$	$16.4 - j6.6$
2195	$43.6 + j23.1$	$16.3 - j6.9$
2205	$44.2 + j23.3$	$16.1 - j7.2$

[1] Device input impedance as measured from gate to ground.

[2] Test circuit impedance as measured from drain to ground.

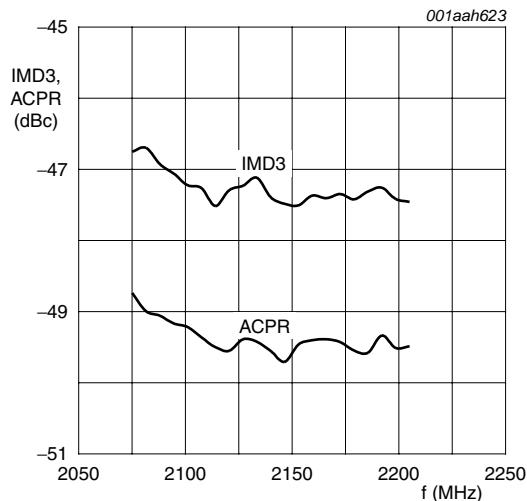
### 8.3 Performance curves

Performance curves are measured in a BLM6G22-30G application circuit.



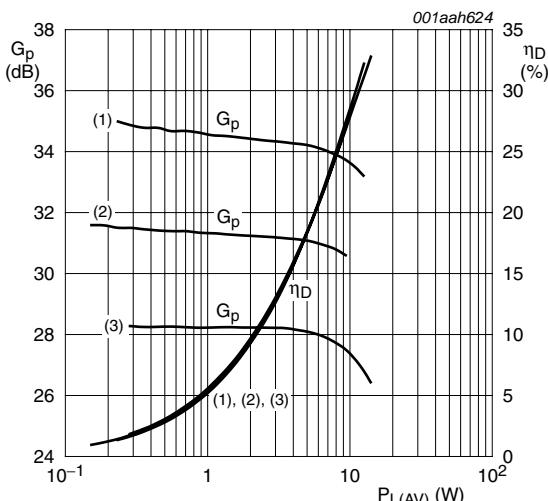
$T_{case} = 25^\circ\text{C}$ ;  $V_{DS} = 28 \text{ V}$ ;  $P_{L(AV)} = 2 \text{ W}$ ;  $I_{Dq1} = 270 \text{ mA}$ ;  $I_{Dq2} = 280 \text{ mA}$ ; carrier spacing = 10 MHz.

**Fig 3.** 2-carrier W-CDMA power gain and drain efficiency as functions of frequency; typical values



$T_{case} = 25^\circ\text{C}$ ;  $V_{DS} = 28 \text{ V}$ ;  $P_{L(AV)} = 2 \text{ W}$ ;  $I_{Dq1} = 270 \text{ mA}$ ;  $I_{Dq2} = 280 \text{ mA}$ ; carrier spacing = 10 MHz.

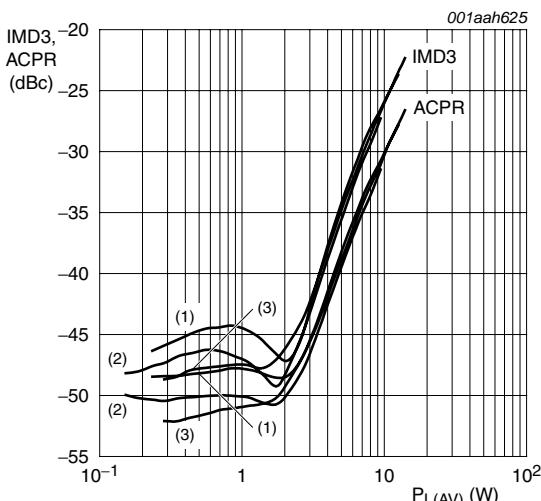
**Fig 4.** 2-carrier W-CDMA adjacent power channel ratio and third order intermodulation distortion as functions of frequency; typical values



$V_{DS} = 28 \text{ V}$ ;  $I_{Dq1} = 270 \text{ mA}$ ;  $I_{Dq2} = 280 \text{ mA}$ ; carrier spacing = 10 MHz.

- (1)  $T_{case} = -30^\circ\text{C}$
- (2)  $T_{case} = 25^\circ\text{C}$
- (3)  $T_{case} = 85^\circ\text{C}$

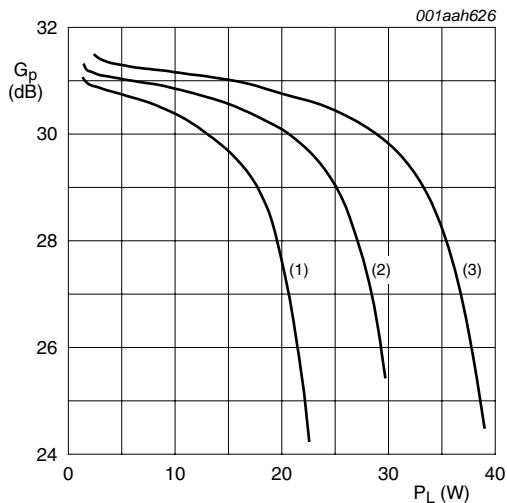
**Fig 5.** 2-carrier W-CDMA power gain and drain efficiency as functions of average output power and temperature; typical values



$V_{DS} = 28 \text{ V}$ ;  $I_{Dq1} = 270 \text{ mA}$ ;  $I_{Dq2} = 280 \text{ mA}$ ; carrier spacing = 10 MHz.

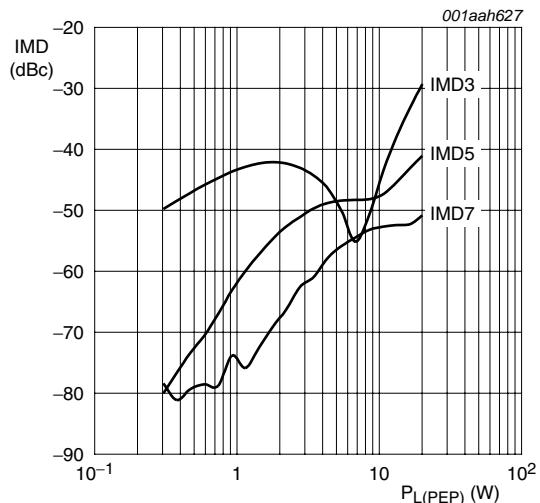
- (1)  $T_{case} = -30^\circ\text{C}$
- (2)  $T_{case} = 25^\circ\text{C}$
- (3)  $T_{case} = 85^\circ\text{C}$

**Fig 6.** 2-carrier W-CDMA adjacent power channel ratio and third order intermodulation distortion as functions of average output power and temperature; typical values



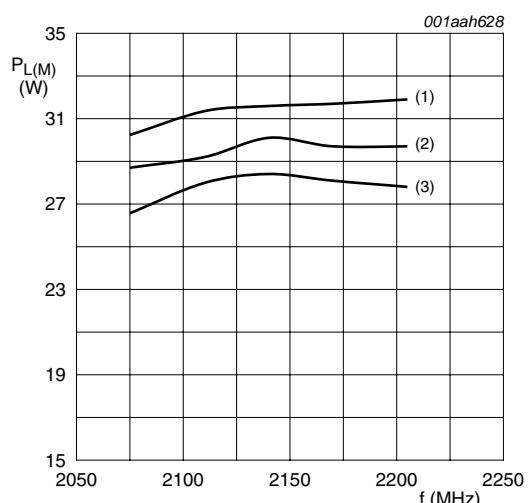
- $f = 2140$  MHz;  $I_{Dq1} = 270$  mA;  $I_{Dq2} = 280$  mA.
- (1)  $V_{DS} = 24$  V
  - (2)  $V_{DS} = 28$  V
  - (3)  $V_{DS} = 32$  V

**Fig 7. One-tone CW power gain as function of output power and drain-source voltage; typical value**



- $I_{Dq1} = 270$  mA;  $I_{Dq2} = 280$  mA;  $f_1 = 2140$  MHz;  $f_2 = 2140.1$  MHz.

**Fig 8. Two-tone CW intermodulation distortion as function of peak envelope load power; typical value**

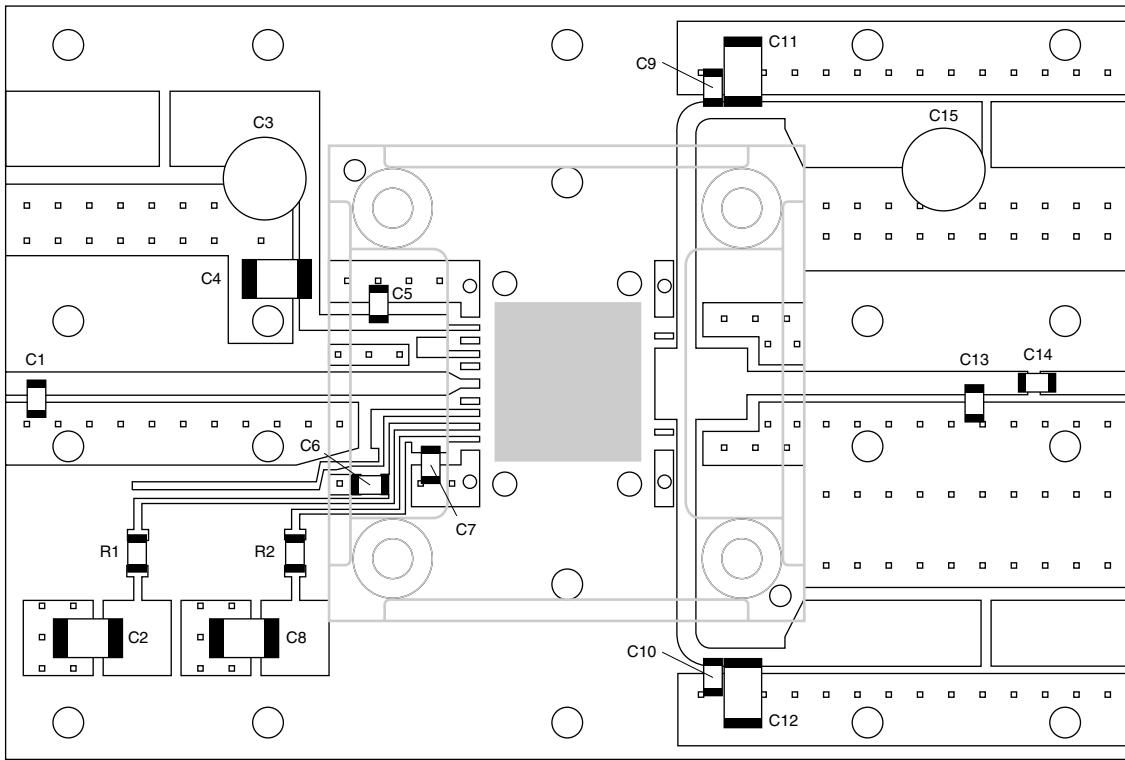


Test signal: IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 to 13). PAR = 9.7 dB at 0.01 % probability on the CCDF.

- (1)  $T_{case} = -30$  °C
- (2)  $T_{case} = 25$  °C
- (3)  $T_{case} = 85$  °C

**Fig 9. Single-carrier peak output power as function of frequency and temperature; typical values**

## 9. Test information



Striplines are on a double copper-clad Rogers 4350B Printed-Circuit Board (PCB) with  $\epsilon_r = 3.5$ ; thickness = 0.76 mm.  
See [Table 8](#) for a list of components.

**Fig 10. Component layout for 2110 MHz to 2170 MHz circuit for 2-carrier W-CDMA**

**Table 8. List of components**

For test circuit see [Figure 10](#).

Component	Description	Value	Remarks
C1, C13	multilayer ceramic chip capacitor	0.3 pF	[1]
C2, C4, C8, C11, C12	multilayer ceramic chip capacitor	4.7 $\mu$ F; 50 V	
C3, C15	electrolytic capacitor	220 $\mu$ F; 35 V	
C5, C9, C10, C14	multilayer ceramic chip capacitor	10 pF	[1]
C6, C7	multilayer ceramic chip capacitor	100 nF	
R1	SMD resistor 0805	1 k $\Omega$	
R2	SMD resistor 0805	3.9 k $\Omega$	

[1] American Technical Ceramics (ATC) type 100A or capacitor of same quality.

## 10. Package outline

HSOP16F: plastic, heatsink small outline package; 16 leads (flat)

SOT834-1

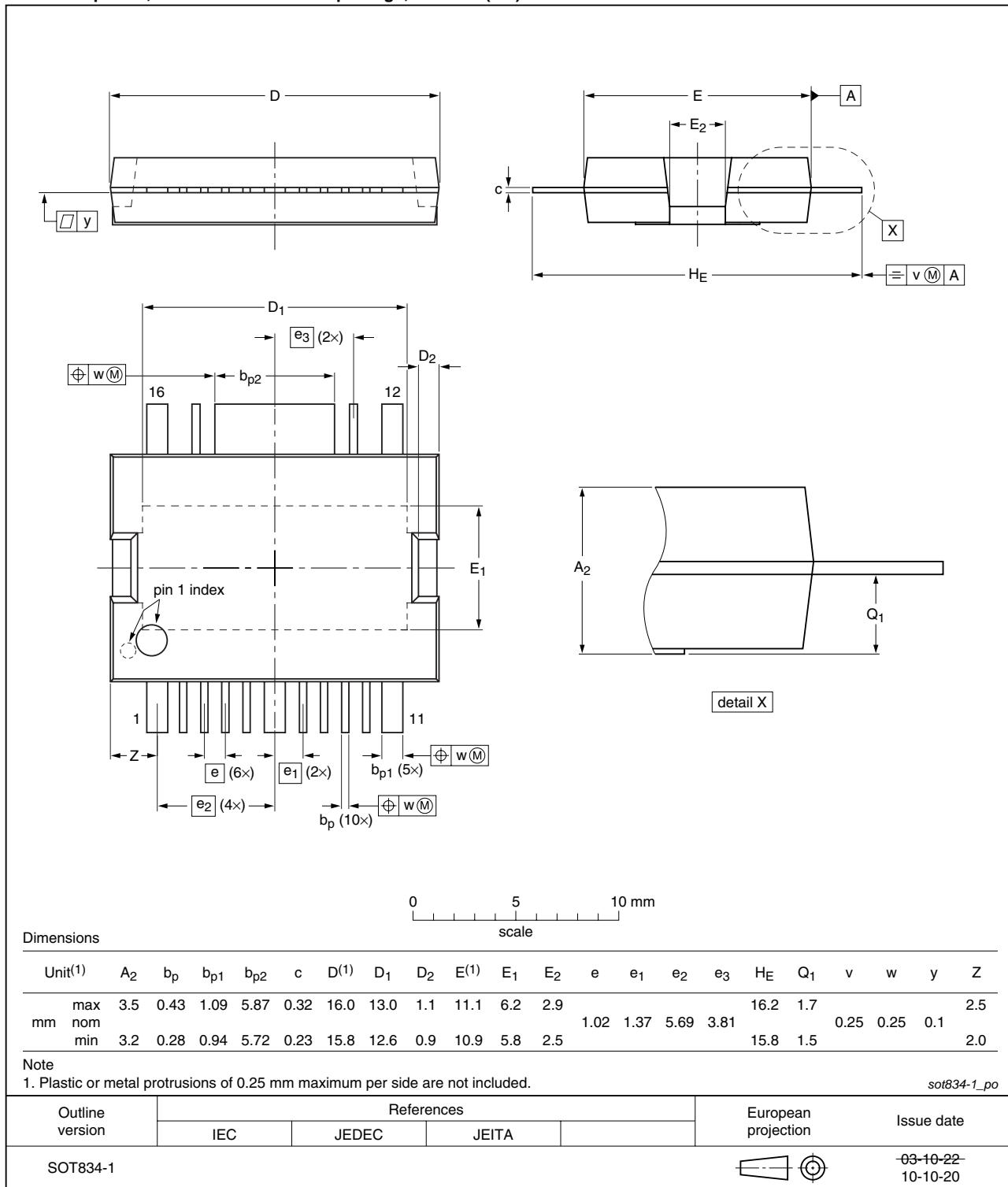


Fig 11. Package outline SOT834-1 (HSOP16F)

HSOP16: plastic, heatsink small outline package; 16 leads

SOT822-1

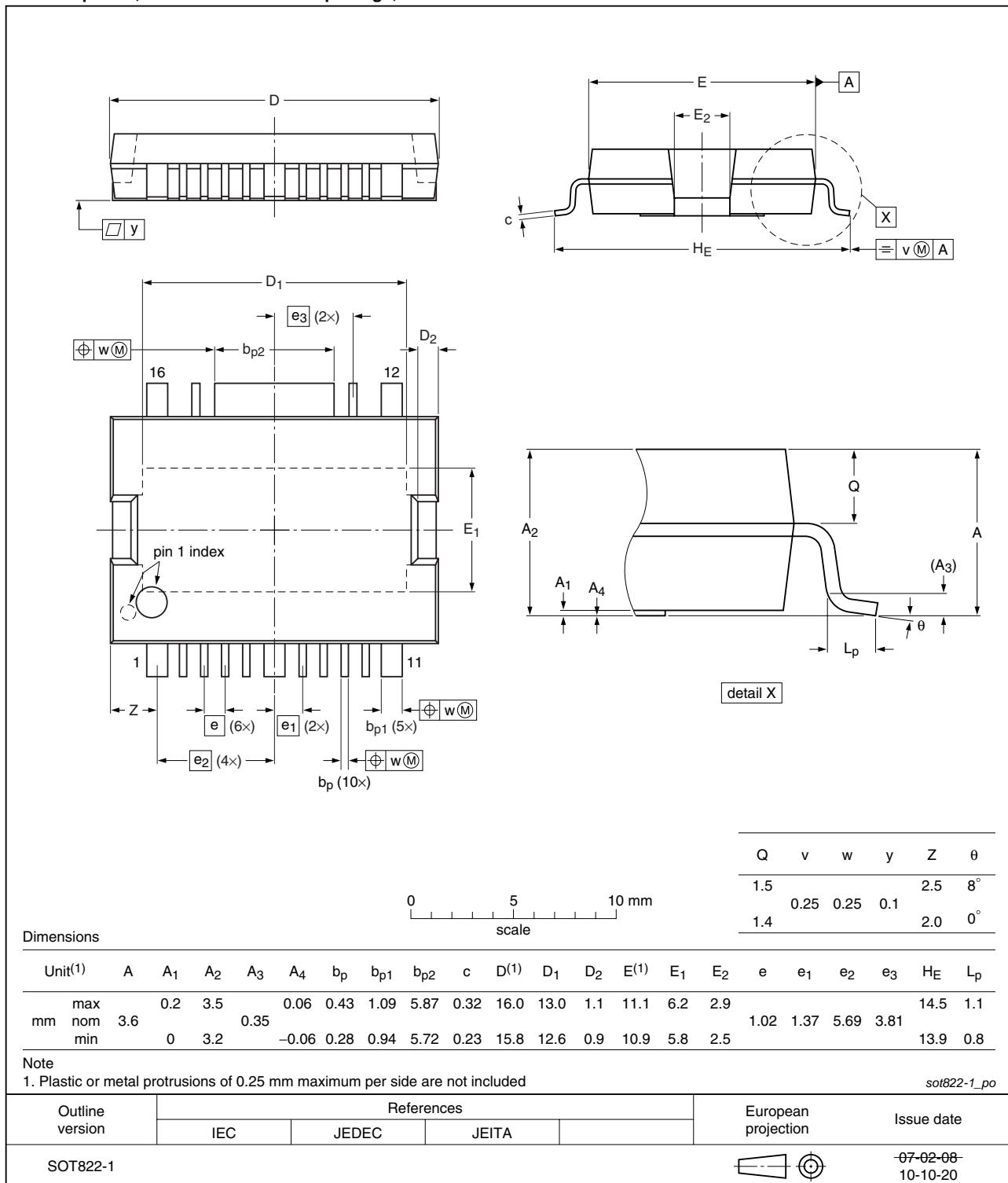


Fig 12. Package outline SOT822-1 (HSOP16)

## 11. Handling information

### 11.1 ESD protection

**Table 9. ESD protection characteristics**

Test condition	Class
Human Body Model (HBM)	1
Machine Model (MM)	1

### 11.2 Moisture sensitivity

**Table 10. Moisture sensitivity level**

Test methodology	Class
JESD-22-A113	3

## 12. Abbreviations

**Table 11. Abbreviations**

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCCH	Dedicated Physical CHannel
IS-95	Interim Standard 95
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
MMIC	Monolithic Microwave Integrated Circuit
PA	Power Amplifier
PAR	Peak-to-Average power Ratio
PDPCH	transmission Power of the Dedicated Physical CHannel
RF	Radio Frequency
VSWR	Voltage Standing-Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

## 13. Revision history

**Table 12. Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLM6G22-30_BLM6G22-30G v.4	20110307	Product data sheet	-	BLM6G22-30_BLM6G22-30G v.3
Modifications:		<ul style="list-style-type: none"><li>• Data sheet status has been changed to "Product data sheet"</li><li>• <a href="#">Table 6 on page 4</a>: the values of RL<sub>in</sub> have been depicted on a negative scale</li></ul>		
BLM6G22-30_BLM6G22-30G v.3	20081121	Preliminary data sheet	-	BLM6G22-30_BLM6G22-30G v.2
BLM6G22-30_BLM6G22-30G v.2	20080904	Preliminary data sheet	-	BLM6G22-30_BLM6G22-30G v.1
BLM6G22-30_BLM6G22-30G v.1	20080303	Objective data sheet	-	-

## 14. Legal information

### 14.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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